# MITIGATION OF THE PROPAGATED DISCHARGES IN GEM STACKS BY HV SCHEME OPTIMIZATION 

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for the ALICE TPC Upgrade

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## ALICE TPC UPGRADE IN NUMBERS

- Currently operated MWPC-chambers will be replaced with new, GEM-based detectors
- Mass production ongoing (see M. Ball's presentation later today) as well as:
- Commissioning and testing of the new chambers
- HV optimization

There is a lot to protect:

- 36x IROC, 36x OROC to be installed in LS2
- 144 quadruple stacks
- 576 GEMs
- 12000 GEM segments
- ${ }^{\sim} 5 \times 10^{9} \mathrm{GEM}$ holes
- 524160 FEE channels


## GEM STACK

- All GEMs segmented on the top side; bottom side not segmented
- Reduce energy of discharges in GEMs
- All segments on a foil connected in parallel via $R_{\mathrm{L}}$ at each segment
- $R_{\mathrm{L}}=5 \mathrm{M} \Omega$


## IROC

- 18 HV segments
- $<A>=92.5 \mathrm{~cm}^{2}$

OROC1

- 20 HV segments
- $\left\langle A>=86.9 \mathrm{~cm}^{2}\right.$


## OROC2

- 22 HV segments
- $\left\langle A>=104.5 \mathrm{~cm}^{2}\right.$

OROC3

- 24 HV segments
- $\langle A\rangle=122.1 \mathrm{~cm}^{2}$



## UPGRADED ALICE TPC

## HV scheme



## DISCHARGE PROPAGATION

## DISCHARGE PROPAGATION

- Propagated/secondary discharge:
discharge in transfer or induction gaps triggered by a primary spark in GEM
- Amplitude of such a discharge about a factor 10 larger than primary one.
- Large signal can be associated with the development of a spark between GEM and GEM/padplane

- May be violent: risk of irreversible damage to the detector


## DISCHARGE IN A SINGLE GEM HOLE

## CATHODE

$\approx 1 \mathrm{~cm}$

3 mm

ANODE

## CATHODE

## G티

## ANODE

## SECONDARY DISCHARGE IN THE INDUCTION GAP

## CATHODE

GEM
ANODE

## CATHODE

GEM

## ANODE

## FACTS

- Observed at relatively low fields, much below amplification field:
- $\mathrm{E}_{\mathrm{\alpha}>0} \sim 5 \mathrm{kV} / \mathrm{cm}\left(\mathrm{Ne}-\mathrm{CO}_{2}-\mathrm{N}_{2}\right)$
- $\mathrm{E}_{\alpha>0} \sim 9 \mathrm{kV} / \mathrm{cm}\left(\mathrm{Ar}-\mathrm{CO}_{2}\right)$
- Field increase in the gap?
- Not confirmed by measurements with HV probes
- Foil bending excluded
- Propagation probability drops with increasing value of the resistor in series on the bottom side of GEM (!) (more recent results in backup)
- Relatively long time intervals between primary and propagated discharge (up to 50 us)
- Ion related?
- Shorter times measured in Ne-based mixtures (mobility)
- Measurements continue (CERN, TUM) Fruitful discussions with the GDD group.




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Fruitful discussions with the GDD group.

- Hope to solve the puzzle soon!



## HV SCHEME OPTIMIZATION

## RC IN THE SYSTEM



- PS impedance
- $10 \mathrm{k} \Omega$ shunt in current meter connected to GEM4TOP channel
- $\quad \sim 10 \mathrm{nF}$ capacitance of a $\sim 80 \mathrm{~m}$ HV cable
- Decoupling resistor (1 per HV cable, top and bottom side)
- Decouple HV supply line form a GEM electrode
- Current choice: $100 \mathrm{k} \Omega$; acceptable potential drop
- $\quad \sim 100 \mathrm{pF}$ capacitance of $\mathrm{a} \sim 1 \mathrm{~m} \mathrm{HV}$ cable
- Loading resistors (top side of the foil)
- Quench a spark, reduce current, protect GEM segment
- Reduce current flowing from the PS in case of a short (allow for $n$ shorts in a foil)
- Voltage (thus gain) drop due to the (ion/electron) current
- Final choice: $5 \mathrm{M} \Omega$ (for GEM1,2,3,4)
- PS impedance
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## PARASITIC RC MEASUREMENTS IN Ar-CO $\mathbf{2}_{2}(\mathbf{9 0 - 1 0})$




- Propagation probability does not depend on the loading resistor value
- Nominal value $R_{\mathrm{L}}=5 \mathrm{M}$
- Extra capacitance (e.g. cable) between the top loading resistor and the top GEM electrode may influence the propagation behavior


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- Extra capacitance (e.g. cable) between the top loading resistor and the top GEM electrode may influence the propagation behavior
- Effect of an extra energy reservoir, causes substantial increase of GEM Bot voltage
$\checkmark$ Loading resistors soldered directly at the GEM foil


## PARASITIC RC MEASUREMENTS IN Ar-CO $\mathbf{2}_{2}(\mathbf{9 0 - 1 0})$

- Cable between bottom decoupling resistor and GEM

- Cable between a Power Supply and bottom decoupling resistor


## PARASITIC RC MEASUREMENTS IN Ar-CO $\mathbf{2}_{2}(\mathbf{9 0 - 1 0})$



Cable between bottom decoupling resistor and GEM

- $R_{\mathrm{L}}=5 \mathrm{M} \Omega, R_{\text {dec, bot }}=200 \mathrm{k} \Omega$
- Propagation probability increases with the parasitic
capacitance (cable length ) introduced between $R_{\text {bot }}$ and GEM
- Effect of the stored energy
- Necessary to install decoupling resistors close to the chambers

- Cable between a Power Supply and bottom decoupling resistor
- Effect of the decoupling resistor $\left(R_{\text {dec,bot }}=200 \mathrm{k} \Omega, R_{\mathrm{L}}=5 \mathrm{M} \Omega\right)$
- Cable length (between the PS and $R_{\text {dec,bot }}$ ) does not influence the propagation probability
$\checkmark$ Decoupling resistor decouples long cables well


## MEASUREMENTS IN Ne-CO $-\mathrm{N}_{2}\left(\mathrm{Ne}-\mathrm{CO}_{2}-\mathrm{N}_{2}\right)$



## PARASITIC RC MEASUREMENTS IN Ne-CO $\mathbf{O}_{2}-\mathbf{N}_{2}$



- "Decoupling power" of $10 \mathrm{k} \Omega$ resistor rather poor, visible dependence on the cable length
- Situation improves with larger $R_{\text {dec,bot }}$
- With $\mathrm{R}_{\text {dec,bot }}>100 \mathrm{k} \Omega$ marginal dependency on the cable length
- Higher resistance clearly preferable




## MITIGATION OF PROPAGATED DISCHARGES <br> Summary

- Choose higher value of the decoupling resistance: $R_{\text {dec,bot }}=100 \mathrm{k} \Omega$
- Value of the resistor can be adjusted until final installation but also during the TPC operation
- HV settings with lower fields preferable (e.g. B-settings, $E_{\mathrm{T} 1,2, \mathrm{IND}}=3.5 \mathrm{kV} / \mathrm{cm}$ )
- Minimize cable length between the $R_{\text {dec,bot }}$ and GEM ( $\sim 2 \mathrm{~m}$ )


## TOP DECOUPLING RESISTOR VALUE - $R_{\text {dec,top }}$

For completeness...

- We keep value of the top decoupling resistor same as for the bottom side: $R_{\text {dec,top }}=100 \mathrm{k} \Omega$
- $R_{\text {dec,top }}>0$ needed to decouple HV power supply and 80 m cable from a GEM top electrode
- Otherwise PS connected directly 1.45 mm away from the active GEM area
- $R_{\text {dec,top }}<1 \mathrm{M}$
- Larger GEM4T and ET3 voltages variations with load oscillations
- Damping of the current oscillation amplitude in GEM4T current monitor



## BACKUP

1. Primary discharge probability with 4-GEM readout chambers
2. Cascaded power supply response to a discharge

## DISCHARGE PROBABILITY

## DISCHARGE PROBABILITY

## Influence of HV settings



- Different HV settings have been tested with a

3-GEM configuration

- "Standard" $\rightarrow$ "IBF"
- Standard - optimized for stability (COMPASS)
- IBF $\rightarrow$ optimized for IBF
- Significant drop of stability while using IBF settings with a typical 3-GEM configuration
- 4-GEM configuration, optimized for energy resolution and IBF is also stable against electrical discharges
- Measurements for HV settings similar to A

|  | S-S-S <br> 'standard' HV $G=2000$ | $\begin{gathered} \text { S-S-S-S } \\ I B=3.0 \% \\ \mathrm{G}=2000 \end{gathered}$ | S-LP-LP-S |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | $\begin{aligned} I B & =0.34 \% \\ G & =1600 \end{aligned}$ | $\begin{gathered} I B=0.34 \% \\ \mathrm{G}=3000 \end{gathered}$ | $\begin{aligned} I B & =0.34 \% \\ \mathrm{G} & =5000 \end{aligned}$ | $\begin{aligned} I B & =0.63 \% \\ \mathrm{G} & =2000 \end{aligned}$ |
|  | $\sim 10^{-10}$ |  |  | $<2 \times 10^{-6}$ | $<7.6 \times 10^{-7}$ |  |
| $\begin{aligned} & \hline{ }^{241} \mathrm{Am} \\ & \mathrm{E}_{\alpha}=5.5 \mathrm{MeV} \\ & \text { rate }=11 \mathrm{kHz} \end{aligned}$ |  |  |  |  |  | $<1.5 \times 10^{-}$ |
| $\begin{aligned} & { }^{239} \mathrm{Pu}+{ }^{241} \mathrm{Am}+{ }^{244} \mathrm{Cm} \\ & \mathrm{E}_{\alpha}=5.2+5.5+5.8 \mathrm{MeV} \\ & \text { rate }=600 \mathrm{~Hz} \end{aligned}$ |  | $<2.7 \times 10^{-9}$ | $<2.3 \times 10^{-9}$ | $(3.1 \pm 0.8) \times 10^{-8}$ |  | $<3.1 \times 10^{-9}$ |
| $\begin{aligned} & \hline{ }^{90} \mathrm{Sr} \\ & \mathrm{E}_{\beta}<2.3 \mathrm{MeV} \\ & \text { rate }=60 \mathrm{kHz} \end{aligned}$ |  |  |  |  | $<3 \times 10^{-12}$ | 25 |

## DISCHARGE PROBABILITY

SPS, December 2014 (RD51 test beam)


- $150 \mathrm{GeV} / \mathrm{c}$ pion beam hitting Fe absorber
- $\quad \sim 5 \times 10^{11}$ particles accumulated
- Comparable to the number of particles expected in the TPC during a typical yearly $\mathrm{Pb}-\mathrm{Pb}$ run at a collision rate of 50 kHz (per GEM stack)
- HV settings comparable to "Settings B", gain = 2000
- Discharge probability: $(6 \pm 4) \times 10^{-12}$ per incoming hadron
- Estimate for Run 3:
- 650 discharges in the TPC per typical yearly $\mathrm{Pb}-\mathrm{Pb}$ run
- 5 per stack


## DISCHARGE PROBABILITY

## LHC, operation at P2



- Test IROCs and OROCs under radiation conditions that are comparable to Run 3
- IROC and OROC are placed in the miniframe, close to the beam pipe
- In 150 kHz pp, direct load on ROCs in this position is comparable to that on ROCs installed in the TPC in Run 3
- More on the ROC and CPS tests at P2 $\rightarrow$ see talk by Robert Münzer

|  | Running time | Current spikes <br> $(>500 \mathrm{nA})$ | Spikes per Pb-Pb year <br> $(\sim 200 \mathrm{~h})$ per stack |
| :---: | :---: | :---: | :---: |
| Settings A (100\%) <br> Gain 2500 | 33h $17^{\prime} 55^{\prime \prime}$ | 30 | 180 |
| Settings B $(100 \%)$ <br> Gain 2000 | $504 \mathrm{~h} 46^{\prime} 08^{\prime \prime}$ | 7 | 3 |
| Settings B (102\%) <br> Gain $\sim 4000$ | $25 \mathrm{~h} 37^{\prime} 19^{\prime \prime}$ | 7 | 55 |

- Settings with lower $\Delta \mathrm{V}_{\text {GEM4 }}$ and $\Delta \mathrm{V}_{\text {GEм3 }} / \Delta \mathrm{V}_{\text {GEM } 4}=1.0$ preferable (settings B )


## CASCADED PS RESPONSE ON A DISCHARGE

## PCB GEM SIMULATOR

ALICE


- 4GEM
- IROC equivalent
- $R_{\mathrm{L}}=5 \mathrm{M} \Omega$
- $R_{\text {dec }}=100 \mathrm{k} \Omega$
- Test Probes: 10:1, 100:1, 1000:1
- Readout via
2.2 nF decoupling C or directly at the HV line (1000:1 probe)
- Discharge/short:
relay - trip behavior
GDT - discharge behav.


## CASCADED PS TESTS

## ISEG prototype

- Check different tripping modes
- Don't turn the channel off
(voltage drops to maintain the current limit)
- Single channel trip after overcurrent detected
- With or w/o ramp-down, delay, etc.
- All channels turn off without ramp after overcurrent detected (ISEG feature)



## CASCADED PS TESTS

## Single channel reaction settings

- Possible small overvoltage $\mathcal{O}(\mathrm{V})$ in a discharge moment (for other-than-discharging GEM)
- No reaction of other channels (unless due to capacitive coupling, few volts)
- All CPS reactions on >1 ms scale, (longer than the discharge/propagation time-scale)
- All reactions safe for GEMs



## CASCADED PS TESTS

## All channels turned off without ramp (ISEG feature)

- All electrodes discharge to ground with a long time constant (RC ~2s, no direct connection to GND)
- All channels trip together within 1 ms
- Overvoltage during a trip excluded or marginal
- No dependency of the PS reaction on the $I_{\text {limit }}$ found




## TESTING CAEN CPS



- CAEN Cascade power supply: second release, current resolution 100 pA
- Crate SY5527LC + GECO program to control and monitor the PS
- Triple GEM stack, $10 \times 10 \mathrm{~cm} 2$ (from RD51), $70 \% \mathrm{Ar}+30 \% \mathrm{CO} 2$
- Resistor $470 \mathrm{k} \Omega$ on the top and $10 \mathrm{k} \Omega$ on the bottom of each GEM (time before final choice was made)
- Reaction on an overcurrent: ramp channel(s) down. No overvoltage measured.
- No possibility to turn all channels off without ramp


## SUMMARY II

- Discharge probability for the nominal S-LP-LP-S solution compatible with the wellestablished, safe settings for the 3-GEM trackers
- Safe HV scheme identified to minimize the effects of a spark in a GEM and mitigate the risk of a discharge propagation:
- Top side of a GEM foil segmented
- $R_{\mathrm{L}}=5 \mathrm{M} \Omega$ soldered directly at the GEM segment
- Decoupling resistors $R_{\text {dec,bot }}=R_{\text {dec,top }}=100 \mathrm{k} \Omega$
- Decoupling resistors need to be installed close to the chambers
- CPS reaction on a discharge event safe for the foils in a GEM stack


## BACKUP SLIDES

## IROC SEGMENTATION

## 18 HV segments on one side

(opposite side not segmented)

- Reduce energy of discharges
- Connected in parallel via $R_{L}$ at each segment

Average area: $92.5 \mathrm{~cm}^{2}$

Follows the padplane layout
Pad size: $7.5 \times 4 \mathrm{~mm}^{2}$
Segment boundaries overlap with pad-row boundaries

| 6 pad rows | $96.4 \mathrm{~cm}^{2}$ |
| :---: | :---: |
| 6 pad rows | $92.4 \mathrm{~cm}^{2}$ |
| 6 pad rows | $88.8 \mathrm{~cm}^{2}$ |
| 6 pad rows | $85.3 \mathrm{~cm}^{2}$ |
| 7 pad rows | $95.2 \mathrm{~cm}^{2}$ |
| 7 pad rows | $90.3 \mathrm{~cm}^{2}$ |
| 8 pad rows | $97.4 \mathrm{~cm}^{2}$ |
| 8 pad rows | $91.1 \mathrm{~cm}^{2}$ |
| 9 pad rows | $95.3 \mathrm{~cm}^{2}$ |



## - OROC3

24 segments
<A> = $122.1 \mathrm{~cm}^{2}$
Pad: $15 \times 6 \mathrm{~mm}^{2}$

- OROC2

22 segments
<A> $=104.5 \mathrm{~cm}^{2}$
Pad: $=12 \times 6 \mathrm{~mm}^{2}$

## - OROC1

20 segments
<A> $=86.9 \mathrm{~cm}^{2}$
Pad: $=10 \times 6 \mathrm{~mm}^{2}$

- Opposite sides not segmented
- Segmentation follows the padplane layout.

| 2 pad rows | $138.9 \mathrm{~cm}^{2}$ |
| :---: | :---: |
| 2 pad rows | $123.6 \mathrm{~cm}^{2}$ |
| 2 pad rows | $122.0 \mathrm{~cm}^{2}$ |
| 2 pad rows | $120.5 \mathrm{~cm}^{2}$ |
| 2 pad rows | $118.9 \mathrm{~cm}^{2}$ |
| 2 pad rows | $117.3 \mathrm{~cm}^{2}$ |
| 2 pad rows | $115.7 \mathrm{~cm}^{2}$ |
| 2 pad rows | $114.1 \mathrm{~cm}^{2}$ |
| 2 pad rows | $112.6 \mathrm{~cm}^{2}$ |
| 2 pad rows | $111.0 \mathrm{~cm}^{2}$ |
| 2 pad rows | $109.4 \mathrm{~cm}^{2}$ |
| 3 pad rows | $161.9 \mathrm{~cm}^{2}$ |
| 2 pad rows | $83.8 \mathrm{~cm}^{2}$ |
| 2 pad rows | $82.5 \mathrm{~cm}^{2}$ |
| 2 pad rows | $81.5 \mathrm{~cm}^{2}$ |
| 3 pad rows | $120.7 \mathrm{~cm}^{2}$ |
| 3 pad rows | $118.4 \mathrm{~cm}^{2}$ |
| 3 pad rows | $116.1 \mathrm{~cm}^{2}$ |
| 3 pad rows | $113.8 \mathrm{~cm}^{2}$ |
| 3 pad rows | $111.6 \mathrm{~cm}^{2}$ |
| 3 pad rows | $109.3 \mathrm{~cm}^{2}$ |
| 3 pad rows | $107.0 \mathrm{~cm}^{2}$ |
| 3 pad rows | $105.0 \mathrm{~cm}^{2}$ |
| 3 pad rows | $84.6 \mathrm{~cm}^{2}$ |
| 3 pad rows | $82.8 \mathrm{~cm}^{2}$ |
| 3 pad rows | $81.2 \mathrm{~cm}^{2}$ |
| 3 pad rows | $79.2 \mathrm{~cm}^{2}$ |
| 3 pad rows | $78.0 \mathrm{~cm}^{2}$ |
| 3 pad rows | $76.5 \mathrm{~cm}^{2}$ |
| 4 pad rows | $99.7 \mathrm{~cm}^{2}$ |
| 4 pad rows | $96.9 \mathrm{~cm}^{2}$ |
| 4 pad rows | $94.1 \mathrm{~cm}^{2}$ |
| 4 pad rows | $96.0 \mathrm{~cm}^{2}$ |
|  |  |
|  |  |

## PS TEST WITH THE GEM-PCB SIMULATOR

## TRIP CHARACTERISTICS

ISEG EHS 8060n - independent channels PS

- After simultaneous trip, particular foil discharges to 0 properly with a proper HV scheme (resistors to ground for each electrode)
- There are significant time delays between trips of subsequent channels
- Global trip $\sim 150 \mathrm{~ms}$ (up to 1000 ms ) later than the first trip of sparking channel
- In sparking channel, usually top and bottom side trips simultaneously, if current limits OK
- Trip in one channel may induce faster trip in another one
- Wrong current limits may result in increase of GEM voltages!


## ALL CHANNELS TO GROUND



- Long discharge time
- RC~2 s (but GEM1)
- ET3 increases first
- Slow discharge time due to non-direct grounding of the electrodes


## TURN ALL CHANNELS OFF WITHOUT RAMP

## Internal delay time

V Turn the channel off when reaching this current. Turn off after:
Channel Configuration

- Turn channel off with ramp

Turn channel off without ramp

- Turn all channels off without ramp

Note: Delayed Trip is only available in mode Kill Disable. Note: The Voltage Ramp Speed will be limited to $1 \%$ when Delayed Trip is enabled.

OK


- No "software" delay (0 ms)
- Hardware delay $\sim 20 \mathrm{~ms}$
- Reaction time >> discharge time


## TURN ALL CHANNELS OFF WITHOUT RAMP

Trip delays between channels

when Delayed Trip is enabled.

- All channels react (trip) within 0.0-1.5 ms
- Different slopes in the first moments may spoil the exact start-time location
- Different primary slopes $\rightarrow$ RC related, observed same differences many times.
- Same when tripping with different $\mathbf{I}_{\text {limit }}$ and trip delay settings
- GEM3T start tripping with a slight voltage increase
- Voltage to GND after ~3 ms
- Related to low $\mathrm{E}_{\mathrm{T} 3}$, voltage drop across $R_{\mathrm{dec}}=100 \mathrm{k}$
- Not observed with higher $\mathrm{E}_{\mathrm{T} 3}$


## TURN ALL CHANNELS OFF WITHOUT RAMP

## Search for an overvoltage -discharge moment

- GEM2 relay "discharge"

Caliz Set Current Trip

- Realistic signal amplitudes in all channels
- Possible slight overvoltage in GEM1 ( $\sim 2 \mathrm{~V}$ for $\sim 10$ us)?
- Confirmed with SPICE; low amplitude signal on GEM1T due to reading out "full" foil
- In reality, overvoltage negligible
- Natural reaction of the system, not related to the CPS


## TURN ALL CHANNELS OFF WITHOUT RAMP

Search for an overvoltage - foil discharge time constants

Cil Set Current Trip
$8 x$

- Tripping channels studied with

- 10:1 test probes via 2.2 nF capacitor (yellow/blue)
- 1000:1 probes connected directly to a GEM-segment capacitor
- Tripping channel connected via 80 m cables, all resistors in place
- Discharging RC ~2s
- No sign of an overvoltage on a large time scale $\mathcal{O}(\mathrm{s})$
- In first 50 ms of a trip, discharging speed may be higher for $\mathrm{GEM}_{\text {Bot }}$ which does not translate to an overvoltage



## TESTING CAEN CPS

- The discharge was induced by the increase of the voltage on the top of GEM 3
- The oscilloscope was triggered with the signal from the readout plane
- We monitor the voltage on the top of each GEM

- Another case where we induced the discharge by increasing the voltage on the top of GEM 2

- Large variations in the current read in CAEN PS compare to Keithley Nevertheless the measured values are similar
- From the discharge studies the oscillations observed on the voltage are related with the current generation mode of the power supply, which works to keep the voltage under control
- In this module it is not possible kill the voltage once the power supply trip - this will be possible on the next version of the power supply


# GEM4 RESISTORS 

## Voltage drops and \#shorts

## CASCADED PS

*Load currents were scaled according to active are of GEM4

| $\begin{gathered} \mathbf{R}_{\mathrm{L}} \\ (\mathrm{M} \mathbf{\Omega}) \end{gathered}$ | $\Delta \mathrm{U}_{\text {GEM4 }}($ Nominal $)-\Delta \mathrm{U}_{\text {GEM4 }}($ Load $) ~[V] ~$ |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | 0 shorts |  |  | 1 short* | 2 shorts | 3 shorts | 4 shorts | 5 shorts | 6 shorts |
|  | 10k | 50k | 100k | 10k | 10k | 10k | 10k | 10k | 10k |
| 1 | 1.5 | 2.3 | 3.2 | 12.0 | 22.0 | - | - | - | - |
| 1.5 | 2.1 | 2.9 | 3.8 | 9.2 | 16.0 | 22.5 | 28.8 | - | - |
| 2.0 | 2.8 | 3.5 | 4.4 | 8.1 | 13.3 | 18.3 |  | 27.9 | - |
| 2.5 | 3.4 | 4.1 | 5.0 | 7.7 | 11.8 | 15.9 |  |  | 27.6 |
| 3.0 | 4.0 | 4.8 | 5.6 | 7.6 | 11.1 | 14.5 |  |  |  |
| 4.0 | 5.3 | 6.0 | 6.9 | 7.9 | 10.6 | 13.2 |  |  |  |
| 5.0 | 6.5 | 7.2 | 8.1 | 8.7 | 10.8 | 12.9 |  |  |  |

- Voltage drops can be compensated by increasing $U_{\text {GEM }}(\sim 390 \mathrm{~V}$ in case of $4,5,6, \ldots$ shorts, max 400V)
- Number of shorts given by 1 mA maximum current of the PS channel

$$
\text { (no. Shorts * } 359 \mathrm{~V}) / \mathrm{R}_{\mathrm{L}}<1 \mathrm{~mA}
$$

- test Cascaded PS with shorts and increased currents...performance the same?


## 0.5 mA RC

*Load currents were scaled according to active are of GEM4

| $\begin{gathered} \mathbf{R}_{\mathrm{L}} \\ (\mathrm{M} \mathbf{\Omega}) \end{gathered}$ | $\Delta \mathrm{U}_{\text {GEM4 }}($ Nominal $)-\Delta \mathrm{U}_{\text {GEM4 }}($ Load $) ~[V] ~$ |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | 0 shorts |  |  | 1 short* | 2 shorts | 3 shorts | 4 shorts | 5 shorts | 6 shorts |
|  | 10k | 50k | 100k | 10k | 10k | 10k | 10k | 10k | 10k |
| 1 | 11.5 | 12.3 | 13.2 | 150.6 | - | - | - | - | - |
| 1.5 | 12.2 | 12.9 | 13.8 | 119.0 | 175 | - | - | - | - |
| 2.0 | 12.8 | 13.6 | 14.4 | 99.5 | 151 | - | - | - | - |
| 2.5 | 13.5 | 14.2 | 15.1 | 86.3 | 134 | 167 | - | - | - |
| 3.0 | 14.1 | 14.8 | 15.7 | 77.0 | 120 | 151 | 177 | - | - |
| 4.0 | 15.3 | 16.0 | 16.9 | 64.6 | 101 | 129 | 153 | 172 | - |
| 5.0 | 16.6 | 17.3 | 18.2 | 57.1 | 89 | 114 | 136 | 154 | 170 |

- Decoupling resistor value may depend on where do we plan to put the RC (more SPICE + stability)
- All voltages affected $\rightarrow$ have to consider all 4+4 fields! (Today only GEM4 voltages considered)
- With a single short, GEM4 is affected substantially, additional resistance in series can compensate although not immediately (access or smart RC deisgn)
- $\quad$ No compensation possible if $R /($ no. shorts $)<R_{G E M 4}$


## 1.0 mA RC (COMPASS-LIKE)

*Load currents were scaled according to active are of GEM4

| $\begin{gathered} R_{\mathrm{L}} \\ (\mathrm{M} \mathbf{\Omega}) \end{gathered}$ | $\Delta \mathrm{U}_{\text {GEM4 }}($ Nominal $)-\Delta \mathrm{U}_{\text {GEM4 }}($ Load $) ~[V] ~$ |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | 0 shorts |  |  | 1 short* | 2 shorts | 3 shorts | 4 shorts | 5 shorts | 6 shorts |
|  | 10k | 50k | 100k | 10k | 10k | 10k | 10k | 10k | 10k |
| 1 | 6.5 | 7.2 | 8.1 | 96.5 | 149 | - | - | - | - |
| 1.5 | 7.1 | 7.9 | 8.8 | 72.0 | 117 | 150 | - | - | - |
| 2.0 | 7.8 | 8.5 | 9.4 | 59.0 | 97 | 127 | 150 | 170 | - |
| 2.5 | 8.4 | 9.1 | 10.0 | 50.0 | 84 | 110 | 132 | 151 | 167 |
| 3.0 | 9.0 | 9.7 | 10.6 | 44.6 | 74 | 98 | 119 | 136 | 152 |
| 4.0 | 10.3 | 11.0 | 11.9 | 37.8 | 61 | 82 | 99 | 115 | 131 |
| 5.0 | 11.5 | 12.2 | 13.1 | 33.6 | 53 | 71 | 86 | 101 | 113 |

- All voltages affected $\rightarrow$ have to consider all 4+4 fields! (Today only GEM4 voltages considered)
- With a single short, GEM4 is affected substantially, additional resistance in series can compensate although not immediately (access or smart RC deisgn)
- No compensation possible if $R_{J} /($ no. shorts $)<R_{\text {GEM }}$


## 2.0 mA RC

*Load currents were scaled according to active are of GEM4

| $\begin{gathered} R_{\mathrm{L}} \\ (\mathrm{M} \mathbf{\Omega}) \end{gathered}$ | $\Delta \mathrm{U}_{\text {GEM4 }}($ Nominal $)-\Delta \mathrm{U}_{\text {GEM4 }}($ Load $) ~[V] ~$ |  |  |  |  |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | 0 shorts |  |  | 1 short* | 2 shorts | 3 shorts | 4 shorts | 5 shorts | 6 shorts |
|  | 10k | 50k | 100k | 10k | 10k | 10k | 10k | 10k | 10k |
| 1 | 4.0 | 4.7 | 5.6 | 58.0 | 98 | 129 | 153 | 173 | - |
| 1.5 | 4.6 | 5.3 | 6.2 | 42.4 | 73 | 98 | 120 | 137 | 154 |
| 2.0 | 5.2 | 5.9 | 6.8 | 34.3 | 59 | 81 | 99 | 115 | 130 |
| 2.5 | 5.8 | 6.6 | 7.5 | 29.6 | 50 | 68 | 84 | 100 | 113 |
| 3.0 | 6.5 | 7.2 | 8.1 | 26.2 | 44 | 60 | 75 | 88 | 101 |
| 4.0 | 7.7 | 8.4 | 9.3 | 22.8 | 37 | 49 | 61 | 72 | 83 |
| 5.0 | 9.0 | 9.7 | 10.6 | 20.8 | 32 | 43 | 53 | 63 | 72 |

- All voltages affected $\rightarrow$ have to consider all 4+4 fields! (Today only GEM4 voltages considered)
- With a single short, GEM4 is affected substantially, additional resistance in series can compensate although not immediately (access or smart RC deisgn)
- No compensation possible if $R_{J} /($ no. shorts $)<R_{\text {GEM }}$


## SUMMARY TABLE: $R_{\mathrm{L}}$ @ GEM4

| $\begin{gathered} R_{\mathrm{L}} \\ (\mathrm{M} \Omega) \end{gathered}$ | 0.5 mA RC |  |  | 1.0 mA RC |  |  | 2.0 mA RC |  |  | CASCADED |  |  |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | 10k | 100k | \#shorts | 10k | 100k | \#shorts | 10k | 100k | \#shorts | 10k | 100k | \#shorts |
| 1.0 | 11.5 | 13.2 | 1 | 6.5 | 8.1 | 2 | 4.0 | 5.6 | 5 | 1.5 | 3.2 | 2 |
| 1.5 | 12.2 | 13.8 | 2 | 7.1 | 8.8 | 4 | 4.6 | 6.2 | 8 | 2.1 | 3.8 | 4 |
| 2.0 | 12.8 | 14.4 | 2 | 7.8 | 9.4 | 5 | 5.2 | 6.8 | 11 | 2.8 | 4.4 | 6 |
| 2.5 | 13.5 | 15.1 | 3 | 8.4 | 10.0 | 6 | 5.8 | 7.5 | 13 | 3.4 | 5.0 | 6 |
| 3.0 | 14.1 | 15.7 | 4 | 9.0 | 10.6 | 8 | 6.5 | 8.1 | 16 | 4.0 | 5.6 | 8 |
| 4.0 | 15.3 | 16.9 | 5 | 10.3 | 11.9 | 11 | 7.7 | 9.3 | 22 | 5.3 | 6.9 | 11 |
| 5.0 | 16.6 | 18.2 | 6 | 11.5 | 13.1 | 13 | 9.0 | 10.6 | 27 | 6.5 | 8.1 | 13 |

## SUMMARY TABLE (AVERAGE)



## DAMPING EFFICIENCY



## DAMPING EFFICIENCY



